

AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

LISTING OF CLAIMS:

1. (currently amended) A method of measuring optical radiation with a spectrometer, the method comprising

illuminating an entrance slit (104, 204, 232, 308, 500, 600) of the spectrometer with optical radiation;

imaging the entrance slit (104, 204, 232, 308, 500, 600) to an optical modulator (108, 210, 238, 318, 406, 510, 604);

dispersing the entrance slit (104, 204, 232, 308, 500, 600) image into a spectrum with a dispersive component (106, 2062, 312, 401, 504, 601);

modulating the spectrum with the optical modulator, the spectrum being composed into a measurement signal with the dispersive element (106, 2062, 312, 401, 504, 605), and

measuring the measurement signal by the spectrometer,
characterized by

imaging the entrance slit (104, 204, 232, 308, 500, 600) to an optical modulator (108, 210, 238, 318, 406, 510, 604), which comprises modulating elements;

dispersing the entrance slit (104, 204, 232, 308, 500, 600) image into a spectrum with the dispersive component (106, 2062, 312, 401, 504, 601) so that each wavelength of the spectrum

forms an image of its own from the entrance slit (104, 204, 234, 308, 500, 600), the place of the image on the elements of the optical modulator (108, 210, 238, 318, 406, 510, 604) depending on the wavelength;

reflecting by a first mirror (208, 236, 316, 508, 601) the optical radiation from the dispersive component (106, 2062, 312, 401, 504, 601) to the optical modulator (108, 210, 238, 318, 406, 510, 604);

modulating the dispersed entrance slit (104, 204, 232, 308, 500, 600) image with at least one element of the optical modulator (108, 210, 238, 318, 406, 510, 604), in which case at least one wavelength band modulated from the entrance slit (104, 108, 232, 308, 500, 600) image is formed;

reflecting by a second mirror (212, 240, 320, 512, 605) the optical radiation from the optical modulator (108, 210, 238, 318, 406, 510, 604) to ~~the~~ an exit slit (104, 214, 242, 322, 514);

directing at least one modulated wavelength band to the dispersive component (106, 2062, 312, 401, 504, 605), which composes non-dispersive measurement radiation from at least one modulated wavelength band so that the entrance slit (104, 204, 232, 308, 500, 600) image at each wavelength band is formed in the same place regardless of the wavelength;

imaging by means of the non-dispersive measurement radiation the entrance slit (104, 204, 232, 308, 500, 600) to an

exit slit (104, 214, 242, 322, 514), which is different from the entrance slit (104, 204, 232, 308, 500, 600); and

detecting, for spectrum measurement, the measurement radiation obtained from the exit slit (104, 214, 242, 322, 514) with one detector (110, 216, 244, 326, 424), which converts the measurement radiation into an electrical measurement signal; and demodulating the electrical measurement signal to separate signal components formed by different wavelength bands from one another and measuring at least one wavelength band with at least one signal component.

2. (original) A method according to claim 1, **characterized** in that the optical modulator (108, 210, 238, 318, 406, 510, 604) is an optical DMD modulator.

3. (original) A method according to claim 1, **characterized** by illuminating the entrance slit (104, 204, 232, 308, 500, 600) with optical radiation emitted by a sample (102, 202, 230, 304).

4. (currently amended) A method according to claim [[1]] 3, **characterized** by illuminating the sample (102, 202, 230, 304) with measurement radiation and imaging the entrance slit (104, 204, 232, 308, 500, 600) to the exit slit (104, 214, 242, 322, 514) by means of the measurement radiation emitted by the sample (102, 202, 230, 304).

5. (original) A method according to claim 1, **characterized** by modulating optical properties of the

elements of the optical modulator (108, 210, 238, 318, 406, 510, 604) as a function of time by modulating different wavelength bands with different waveforms and separating different wavelength bands from one another during measurement by demodulation corresponding to the modulation.

6. (original) A method according to claim 1, **characterized** by modulating optical properties of the elements of the optical modulator (108, 210, 238, 318, 406, 510, 604) as a function of time by multiplexing different wavelength bands using time division and separating different wavelength bands from one another during measurement by demodulation corresponding to the modulation.

7. (original) A method according to claim 1, **characterized** by modulating optical properties of the elements of the optical modulator (108, 210, 238, 318, 406, 510, 604) as a function of time by multiplexing different wavelength bands using frequency division and separating different wavelength bands from one another during measurement by demodulation corresponding to the modulation or by filtering the frequencies apart from one another.

8. (original) A method according to claim 1, **characterized** by modulating optical properties of the elements of the optical modulator (108, 210, 238, 318, 406, 510, 604) as a function of time by multiplexing different wavelength bands using code division and separating different wavelength

bands from one another during measurement by demodulation corresponding to the modulation.

9. (original) A method according to claim 1, **characterized** in that only one dispersive component (106, 2062, 312, 401, 504, 601) is used in the measurement.

10. (currently amended) A method according to claim [[1]] 3, **characterized** by determining the concentration of at least one substance in the sample (102, 202, 230, 304) by means of at least one measured wavelength band.

11. (currently amended) A method according to claim [[1]] 3, **characterized** by determining the thickness of a substance layer in the sample (102, 202, 230, 304) by means of at least one measured wavelength band.

12. (currently amended) A method according to claim [[1]] 3, **characterized** by determining the sample (102, 202, 230, 304) temperature by means of at least one measured wavelength band.

13. (original) A method according to claim 1, **characterized** in that the detector (110, 216, 244, 326, 424) forms the exit slit (104, 214, 242, 322, 514).

14. (original) A method according to claim 1, **characterized** in that the spectrometer is produced for an integrated circuit.

15. (original) A method according to claim 1, **characterized** in that the spectrometer has been produced

using a plane waveguide, LIGA technique and moulded plastic optics.

16. (currently amended) A spectrometer for measuring an optical spectrum, the spectrometer comprising an entrance slit (104, 204, 232, 308, 500, 600), at least one dispersive component (106, 2062, 312, 401, 504, 601, 605), at least one imaging component (106, 206, 234, 314, 402, 506, 516, 602, 606), an optical modulator (108, 210, 238, 318, 406, 510, 604) and an exit slit (104, 214, 242, 322, 514); and

the entrance slit (104, 204, 232, 308, 500, 600) in the spectrometer is arranged to limit the amount of optical radiation entering the spectrometer;

the imaging component (106, 206, 234, 314, 402, 506, 516, 602) is arranged to image the entrance slit (104, 204, 232, 308, 500, 600) to the optical modulator (108, 210, 238, 318, 406, 510, 604);

at least one dispersive component (106, 2062, 312, 401, 504, 601) is arranged to form a spectrum of the entrance slit (104, 204, 232, 308, 500, 600) image, the modulator (108, 210, 238, 318, 406, 510, 604) being arranged to modulate the spectrum and to compose measurement radiation of the modulated spectrum;

the spectrometer is arranged to measure measurement radiation from the exit slit (104, 214, 242, 322, 514),
characterized in that

the spectrometer comprises:

only one detector (110, 216, 244, 326, 424);

the dispersive component (106, 2062, 312, 401, 504, 601) is arranged to disperse the entrance slit (104, 204, 232, 308, 500, 600) image into a spectrum so that each wavelength of the spectrum forms an image of its own from the entrance slit (104, 204, 232, 308, 500, 600), the place of the image on the elements of the optical modulator (108, 210, 238, 318, 406, 510, 604) depending on the wavelength;

a first mirror (208, 236, 316, 508, 601) ~~for~~ positioned so as to reflect the optical radiation from the dispersive component (106, 2062, 312, 401, 504, 601) to the optical modulator (108, 210, 238, 318, 406, 510, 604);

the optical modulator (108, 210, 238, 318, 406, 510, 604) comprising at least one modulating element is arranged to modulate the dispersed entrance slit (104, 204, 232, 308, 500, 600) image with at least one element to form at least one wavelength band modulated from the entrance slit (104, 204, 232, 308, 500, 600) image;

a second mirror (212, 240, 320, 512, 605) ~~for~~ positioned so as to reflect the optical radiation from the optical modulator (108, 210, 238, 318, 406, 510, 604) to the exit slit (104, 214, 242, 322, 514);

the dispersive component (106, 2062, 312, 401, 504, 605) is arranged to compose non-dispersive measurement radiation from at least one modulated wavelength band so that the entrance slit

(104, 204, 232, 308, 500, 600) image at each wavelength band is formed in the same place regardless of the wavelength;

the imaging component (106, 206, 234, 314, 402, 506, 516, 606) is arranged to image by means of measurement radiation the entrance slit (104, 204, 232, 308, 500, 600) to the exit slit (104, 214, 242, 322, 514) which is different from the entrance slit (104, 204, 232, 308, 500, 600);

the only detector (110, 216, 244, 326, 424) of the spectrometer is arranged to detect measurement radiation from the exit slit (104, 214, 242, 322, 514) and to convert the measurement radiation into an electrical measurement signal; and

for spectrum measurement the spectrometer is arranged to demodulate the electrical measurement signal to separate signal components formed by different wavelength bands from one another and to measure at least one wavelength band with at least one signal component.

17. (original) A spectrometer according to claim 16, **characterized** in that the optical modulator (108, 210, 238, 318, 406, 510, 604) is an optical DMD modulator.

18. (original) A spectrometer according to claim 16, **characterized** in that the spectrometer is arranged to illuminate the entrance slit (104, 204, 232, 308, 500, 600) with the optical radiation emitted by a sample (102, 202, 230, 304).

19. (currently amended) A spectrometer according to claim [[16]] 18, **characterized** in that the spectrometer is

arranged to illuminate the sample (102, 202, 230, 304) with measurement radiation and to image the measurement radiation emitted by the sample (102, 202, 230, 304) to the exit slit (104, 214, 242, 322, 514).

20. (original) A spectrometer according to claim 16, **characterized** in that the spectrometer is arranged to modulate optical properties of the elements of the optical modulator (108, 210, 238, 318, 406, 510, 604) as a function of time so that different wavelength bands are modulated with different waveforms and the spectrometer is arranged to separate different wavelength bands from one another with demodulation corresponding to the modulation.

21. (original) A spectrometer according to claim 16, **characterized** in that the spectrometer is arranged to modulate optical properties of the elements of the optical modulator (108, 210, 238, 318, 406, 510, 604) as a function of time so that different wavelength bands are multiplexed using time division and the spectrometer is arranged to separate different wavelength bands from one another with demodulation corresponding to the modulation.

22. (original) A spectrometer according to claim 16, **characterized** in that the spectrometer is arranged to modulate optical properties of the elements of the optical modulator (108, 210, 238, 318, 406, 510, 604) as a function of time so that different wavelength bands are multiplexed using

frequency division and the spectrometer is arranged to separate different wavelength bands from one another with demodulation corresponding to the modulation or with filtering.

23. (original) A spectrometer according to claim 16, **characterized** in that the spectrometer is arranged to modulate optical properties of the elements of the optical modulator (108, 210, 238, 318, 406, 510, 604) as a function of time so that different wavelength bands are multiplexed using code division and the spectrometer is arranged to separate different wavelength bands from one another with demodulation corresponding to the modulation.

24. (original) A spectrometer according to claim 16, **characterized** in that the spectrometer comprises only one dispersive component (106, 2062, 312, 401, 504, 601).

25. (original) A spectrometer according to claim 16, **characterized** in that the spectrometer is produced for one integrated circuit.

26. (currently amended) A spectrometer according to claim ~~[[16]]~~ 18, **characterized** in that the spectrometer is arranged to determine the concentration of at least one substance in the sample (102, 202, 230, 304) by means of at least one measured wavelength band.

27. (currently amended) A spectrometer according to claim ~~[[16]]~~ 18, **characterized** in that the spectrometer is arranged to determine the thickness of a substance layer in the

sample (102, 202, 230, 304) by means of at least one measured wavelength band.

28. (currently amended) A spectrometer according to claim [[16]] 18, **characterized** in that the spectrometer is arranged to determine the sample (102, 202, 230, 304) temperature by means of at least one measured wavelength band.

29. (original) A spectrometer according to claim 16, **characterized** in that the detector (110, 216, 244, 326, 424) is the exit slit (104, 214, 242, 322, 514).

30. (original) A spectrometer according to claim 16, **characterized** in that the spectrometer is produced for an integrated circuit.

31. (original) A spectrometer according to claim 16, **characterized** in that the spectrometer is produced using a plane waveguide, LIGA technique and moulded plastic optics.